

Application/Control No.

Applicant(s)/Patent under Reexamination

10/527,797 Examiner TOMIZAWA ET AL.

John P. Sheehan

1742

SEARCHED				
Class	Subclass	Date	Examiner	
	,			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	9/24/2007	JPS		
74				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	